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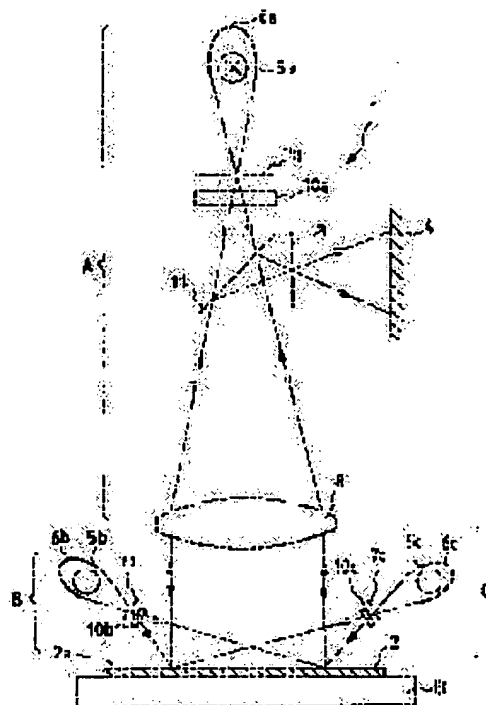
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(54) INSPECTION DEVICE

(57)Abstract:

PURPOSE: To provide a highly contrasted clear contrast pattern by providing a shielding body at a rear side focus or its nearby position so as to cut off a part of the reflecting light heading to the measuring face and also irradiating the light at larger angle of incidence than that of the parallel light to a sample.

CONSTITUTION: A surface 2a of a plate-shaped sample 2 is irradiated with the light in the normal direction and the diagonal direction from each of light sources 5a-5c of light irradiating means A-C, and the reflected light from the sample face 2a is led to a screen 4 via a collimator lens 8, a half mirror 11, and an aperture diaphragm 3 so as to form a contrast pattern. In this way, measurement can be carried out with focusing on the sample face 2a, and also a definition of the contrast pattern is improved as diffused light can be eliminated by the aperture diaphragm 3. As the contrast difference of the contrast pattern can be emphasized by converting the irradiation direction or an angle of incidence by the light irradiation means B, C, the highly contrasted and clear contrast pattern can be obtained.



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